

Energy-Reliability Limits in Nanoscale Circuits

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Abstract

In the nanoscale regime, the behavior of both extant and emerging semiconductor devices are often unreliable. Reliability of such devices often trades-off with their energy consumption, speed, and/or chip area. We study the energy-reliability limits for circuits designed using such devices. Using the mutual information propagation in logic circuits technique developed by Pippenger, together with optimization, we obtain lower bounds on the energy consumption for computing n -input boolean functions. Most extant technologies require all gates to have the same electrical operating point and in circuits of such uniform gates, the minimum energy required to achieve any non-trivial reliability scales superlinearly with the number of inputs. On the other hand, in some emerging technologies such as spin electronics, where the gates in a circuit can have different operating points, energy scaling can be linear in the number of inputs. As part of our development we find a simple procedure for energy allocation across gates in a boolean circuit with different operating points.

Index Terms

fault-tolerant computing, boolean function, logic gate, energy-failure function, optimization, information inequalities

I. INTRODUCTION

As area and energy scaling in CMOS technology saturates, the semiconductor industry has been exploring promising new nanoscale devices [2]. A major challenge, however, in using nanoscale devices is that they can be very unreliable, especially when operated at low energy [3]. This has created renewed interest in the study of reliable circuit design using unreliable components [2], [4], [5].

Von Neumann initiated studies of error in logic circuits from a statistical and thermodynamic point of view [6], showing that repeated computations followed by majority logic can offer reliability even when all components are unreliable. Over the last six decades, this result has inspired intermittent bursts of work on statistical models in computation.

Obtaining bounds on the minimum size of a noisy circuit to compute a function with a given reliability has drawn significant interest, e.g. [7]–[9]. There has also been work to obtain an upper bound on gate noise for which a non-trivial reliability can be achieved [10]–[12]. Another interesting thread of work is the study of unreliable circuits preceded and succeeded by reliable encoding and decoding components, respectively. A lower bound on the ratio of encoded input size to true input necessary for reliable computation was obtained in [13]. Use of encoder and decoder modules has also been employed in memory circuits [14]–[16], where LDPC decoders play an important role. Use of error-correcting codes for fault tolerance in linear dynamical systems have also been investigated [17]. Recently, linear function computation for unreliable encoder, decoder, and computation circuits was studied [18].

As von Neumann was evidently influenced by the success of information theory, efforts have been made to connect information theory and noisy computation [19]. Adding encoder and decoder modules to unreliable circuits [13] was an attempt to establish a correspondence between communication channels and computation circuits. A more natural use of information-theoretic techniques to study noisy circuits was developed much later by Pippenger [11], improvements of which led to the lower bound on the size of a circuit with a desired level of reliability mentioned above [10], [20], [21].

In this work, we study the limits of energy consumption for reliable computation with unreliable components using Pippenger’s information-theoretic technique. Since spin and other nanoscale devices consume more energy

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as they are built to have lower failure rates [3], there is a fundamental tradeoff between reliability and energy consumption. Our goal is to obtain the information-theoretic limit of energy consumption for achieving a desired level of reliability in computation.

A. Contribution

We derive the energy-reliability limits for circuits where all logic gates are constrained to have uniform electrical operating points (Sec. IV), a constraint common in most extant technologies. The main goal here is to understand the scaling of energy consumption with number of inputs. We observe that for both extant and emerging technologies, a superlinear scaling of energy consumption with number of inputs is unavoidable.

As some new technologies promise to relax the constraint of uniformity of operating points, we also study the case where logic gates may operate differently, and hence, consume different energies (Sec. V). Building on Pippenger's method and convex optimization theory, we study the minimum energy needed for a given reliability requirement and vice versa. For certain symmetric circuits we observe that linear scaling of energy consumption is possible. From this study we also obtain a procedure for energy allocation in boolean circuits.

II. SETTING

The goal is to design circuits to compute n -input boolean functions using a single type of gate among the set of universal gates, i.e. NAND and NOR, such that each gate has at most k inputs and exactly one output. Gates are interconnected into a circuit to compute the desired function, such that inputs to gates are some of the n inputs to the function, outputs of other gates in the circuit, or constants $\{0, 1\}$. The output of the circuit is the output of a certain gate. In general, a boolean function can be realized by several different circuits using the same kind of universal gate. Indeed, elementary digital logic design is concerned with minimal realizations [22].

We assume that the boolean function F is sensitive to each input, i.e., for each input i , there is a configuration of other inputs $x_1 = c_1, x_2 = c_2, \dots, x_{i-1} = c_{i-1}, x_{i+1} = c_{i+1}, \dots, x_n = c_n$, such that

$$F(c_1, \dots, c_{i-1}, 0, c_{i+1}, c_n) \neq F(c_1, \dots, c_{i-1}, 1, c_{i+1}, c_n).$$

A boolean function of n inputs which is not sensitive to one of its inputs is equivalent to a function of $n - 1$ inputs.

In combinatorial circuits there is no feedback, i.e., the connections between the gates must form a directed acyclic graph, where gates are vertices and the connections between gates are edges. The input to a gate is considered the head of a directed edge. A special class of combinatorial circuits of interest in this work are *formulas*, where the graph is a directed tree.

A gate may fail to produce a correct output for a given input with probability ϵ . When a gate fails, its output is flipped. This means that for a given input, the output is correct with probability $1 - \epsilon$ and is flipped with probability ϵ . Each gate in a circuit or formula fails independently of each other. This model of gate failure is known as the ϵ -noisy model [6].

The noise probability ϵ of a gate depends on its electrical characteristics such as bias voltage, as well as physical and material properties. These characteristics also determine the energy consumption of the gate. For a given device technology, there is a relationship between energy consumption of the gate and its probability of failure. This function depends on the fundamental nature of the device, whether CMOS or emerging beyond-CMOS technologies such as spin electronics or carbon nanotubes.

Definition 1: For a gate with probability of failure ϵ and energy consumption e_g , let us define the *energy-failure function* of the gate as $\epsilon = \chi(e_g)$.

When we construct circuits from noisy gates, for any given input, there is a probability that the output of a circuit is incorrect.

Definition 2: We say a circuit for the n -input boolean function F is δ -reliable if for any input configuration $\{x_1, x_2, \dots, x_n\} \in \{0, 1\}^n$, the output of the circuit y satisfies the following:

$$\Pr(y = F(x_1, x_2, \dots, x_n)) \geq 1 - \delta,$$

where probability is over all the failure patterns of the gates in the circuit.

This work aims to answer the following general question: What is the minimum energy expenditure needed to realize an n -input boolean function using a δ -reliable formula?¹ Herein, we first restrict attention to circuits (and/or technologies) where each gate in the circuit must have the same operating point and hence consume the same energy. We obtain the minimum energy per device for reliable computation. Some emerging technologies like spin electronics allow different devices in the circuit to have different operating points [23]. The energy-reliability limit with such variable-quality gates is better; we characterize such settings later.

III. PRELIMINARIES

A. Circuit Graphs

An n -input boolean function F_n can be realized using various different formula structures of (universal) logic gates of a given kind. For a given realization, we have a directed graph $G_g = (V_g, \mathcal{E}_g)$, where vertices V_g are the set of gates and $\mathcal{E}_g$ are the edges corresponding to connections between gates. Each edge is directed towards the gate to which it is an input. We call G_g the *gate graph* of the realization of the formula. In this work we only consider formulas, and hence, the corresponding graphs are trees.

Another graph that we use subsequently is the *bit graph* $G_b = (V_b, \mathcal{E}_b)$. Here, V_b corresponds to interconnects/wires in the circuit. In a circuit there are interconnects that run from output of one gate to input of another gate, from circuit inputs to inputs of gates, and from fixed sources (corresponding to permanent 0 or 1) to input of gates. Two nodes in V_b share an edge if the corresponding interconnects are incident to a common gate.

As the circuit is a tree, interconnects between gates have a one-to-one mapping to gates (the gates to which they are outputs). From here it can be seen that G_g is a subgraph of G_b . In addition G_b has leaf nodes that correspond to either inputs or to fixed sources. This relation will be useful later.

B. Pippenger's Method

Pippenger developed the technique of information flow in logic circuits to bound the size of a δ -reliable circuit constructed using ϵ -noisy gates [11], which we review here. For a boolean function F of n -inputs, for any input i there exists a values $c_{\setminus i} \in \{0, 1\}^{n-1}$ such that $F_i(x) := F(c_{\setminus i}, x) = x$ or $\bar{x}$, where $\bar{x}$ is the complement of x . Hence, for any random input X , $F_i(X)$ is a one-to-one mapping. When F is realized using noisy gates, the output is no longer $F_i(X)$, but a random variable Y , depending on the gate noise and G_g .

Note δ is the upper bound on probability of error, $P_e(c_{\setminus i})$ for input configuration $c_{\setminus i}$, and the possible number of values of Y is $M = 2$. Then using Fano's inequality:

$$I(X; Y) \geq H(X) - h(P_e(c_{\setminus i})) - P_e(c_{\setminus i}) \frac{\ln(M-1)}{\ln 2}, \quad (1)$$

where $h(\cdot)$ is the binary entropy function. From the fact $M = 2$, as the output is binary, it follows that:

$$1 - h(\delta) \leq I(X; Y). \quad (2)$$

Note that unlike in communication where $h(P_e)$ is often bounded by 1 to obtain a simplified bound on P_e , here the bound is left in terms of $h(P_e)$.

Finally to bring gate failures into this bound, two important observations are made. First, for a perfect gate g with input random variables $U_1, U_2, \dots, U_k$ and output random variable U_0 , for any random variable Z :

$$\begin{aligned} I(Z; U_0) &\leq I(Z; U_1, U_2, \dots, U_k) \\ &\leq \sum_{i=1}^k I(Z; U_i) \end{aligned} \quad (3)$$

by the data processing inequality and the distributive rule of mutual information [11]. Second, if the gate is ϵ -noisy, then the output is $\tilde{U}_0 = U_0 + N_0$, where N_0 is a Bernoulli(ϵ) random variable independent of U_0 . Then, a strong data processing inequality holds [11], [20], [21]:

$$I(Z; \tilde{U}_0) \leq (1 - 2\epsilon)^2 I(Z; U_0). \quad (4)$$

¹In the presence of unreliable components, minimal realizations may not consume the minimum energy.

A loose version of this strong data processing inequality was first developed by Pippenger, which was later tightened by Evans and Schulman. These works triggered significant research effort on strong data processing inequalities in different contexts, but they are not within the scope of this work.

Based on these two information-theoretic inequalities and some combinatorial arguments, a lower bound on the depth of a formula was obtained in terms of δ and ϵ [11], [20], [21]. There, the gate noise was fixed and the energy consumption was not considered. In this work, we build on this technique to study circuits where energy (and hence, noise) of a gate can be tuned and derive bounds on total energy consumption to realize a boolean function.

C. Energy-Failure Functions

A few special cases of the energy-failure function χ are relevant to modern technologies. Here we will obtain a generic lower bound applicable to a broad class of energy-failure functions that encompass all relevant technologies.

Definition 3: Let the class of *physical* energy-failure functions be ones that satisfy $\chi : (0, \infty) \mapsto (0, a)$, $0 < a \leq 1$, that is strictly decreasing, convex, and differentiable with $\lim_{e_g \rightarrow 0} \chi(e_g) = a$ and $\lim_{e_g \rightarrow \infty} \chi(e_g) = 0$.

Lemma 1: Any physical energy-failure function χ has an inverse χ^{-1} that is strictly decreasing, convex, and differentiable.

Proof: Proof of this lemma is presented in the Appendix. ■

In practice, energy-failure functions of CMOS, carbon nanotube, and spin electronics belong to the class of physical energy-failure functions.

A closed-form expression relating energy and failure for a typical spin device has been derived based on the physics of the device [3]. An approximate form of the functional dependence is

$$\epsilon = \epsilon_0 \exp(-cI),$$

where I is the supply current of the device. Constants $c > 0$ and $\epsilon_0 \in (0, 1]$ depend on the device parameters, like critical current, gate delay, and other switching parameters. As energy consumption scales as square of current, failure ϵ and energy e in a spin device are related as:

$$\epsilon = \epsilon_0 \exp(-c' \sqrt{e}), \text{ with } c' > 0.$$

A generic way to capture this kind of dependence is through stretched exponentials,

$$\epsilon = \epsilon_0 \exp(-ce^\beta),$$

where $\epsilon_0, \beta \in (0, 1]$, and $c > 0$.

For CMOS technologies, it has been shown that the exponential energy-failure function for a gate is a fundamental thermodynamic limit [24].

Polynomial functions are another wide class of energy-failure dependence functions that can be used to approximately characterize different logic devices:

$$\epsilon = \frac{\epsilon_0}{(e + 1)^\beta}, \text{ with } \beta > 0, \epsilon_0 \in (0, 1).$$

IV. UNIFORM GATE OPERATING POINTS

In this section we consider the setting where each gate in the circuit must have the same electrical operating point. This requirement may be due to limitations of the design and fabrication technologies of the electronic devices being used. Some emerging technologies do allow variable gate operations [23], which we discuss in Sec. V.

A. Computation Energy per Input Bit

For an n -input formula F , consider a given realization of the formula using logic gates and hence a given directed gate tree $G_g = (V_g, \mathcal{E}_g)$. For each input bit i ,

$$1 - h(\delta) \leq I(F_i(X); X) \leq (1 - 2\epsilon)^{2|\mathcal{P}_i|},$$

where $\mathcal{P}_i$ is the path in G_g to the output gate from the gate to which x_i is input. This follows by inductively using (3) and (4) along the depth of G_g from root to the terminal gate into which x_i is an input [11], [20], [21].

Thus, for any δ -reliable circuit realization of F with total energy consumption E the following conditions must be satisfied.

$$\begin{aligned} \text{C1. } & 1 - h(\delta) \leq (1 - 2\epsilon)^{2|\mathcal{P}_i|}, \text{ for } 1 \leq i \leq n, \\ \text{C2. } & \chi\left(\frac{E}{|V_g|}\right) = \epsilon. \end{aligned} \quad (5)$$

Condition C1 follows from the definition of δ -reliability of the circuit since for any input bit i and any configuration $c_{\setminus i}$, $\Pr(Y = F_i(X)) \geq 1 - \delta$. Condition C2 relating total energy E and ϵ follows because gates with the same electrical characteristics consume the same energy. Hence, energy consumption per gate is $e_g = \frac{E}{|V_g|}$, which along with $\epsilon = \chi(e_g)$ implies the condition.

Our goal is to find a lower bound on the total energy consumption E in a circuit realization of F . This implies that a set of conditions weaker than C1 and C2 would give a lower bound on E . Hence, we develop the following weaker conditions.

$$\begin{aligned} \text{C3. } & \frac{1}{4} \ln \frac{1}{1 - h(\delta)} \geq |\mathcal{P}_i| \epsilon, \text{ for } 1 \leq i \leq n, \\ \text{C4. } & \chi\left(\frac{E}{|V_g|}\right) = \epsilon. \end{aligned} \quad (6)$$

Note that conditions C2 and C4 are identical, but we give them different names for convenience.

The following lemma formally relates the conditions C3 and C4 to the conditions C1 and C2.

Lemma 2: For a given formula F , a realization gate tree $G_g = (V_g, \mathcal{E}_g)$, and required reliability δ , if E satisfies conditions C1 and C2, then it also satisfies conditions C3 and C4.

Proof: We need only consider the relation between C1 and C3. The proof follows by noting that

$$1 - x \leq \exp(-x),$$

which implies that if (5) is satisfied for a given E , then for that E :

$$1 - h(\delta) \leq \exp(-4|\mathcal{P}_i| \epsilon), \text{ for } 1 \leq i \leq n.$$

Taking the natural logarithm of both sides does not disturb the inequality since $\ln(\cdot)$ is monotonic. Thus we obtain the desired result by multiplying both sides by -1 and flipping the inequality. ■

Due to linear dependence on graph structure, condition C3 is more tractable than C1. As we discuss later, these conditions lead to a closed-form expression for the lower bound on energy consumption.

It is apparent from the necessary conditions we have just established that the lower bound on energy consumption will depend on the relationship between probability of failure of a gate and its energy consumption. Intuitively, when probability of failure of a gate decays faster with its energy consumption, the total energy consumption of the circuit should also be lower.

Lemma 3: For physical energy-failure functions χ and for a given n -input boolean function F with realization graph $G_g = (V_g, \mathcal{E}_g)$,

$$E \geq |V_g| \chi^{-1} \left(\frac{1}{4 \max_i |\mathcal{P}_i|} \ln \frac{1}{1 - h(\delta)} \right),$$

for $\delta < \frac{1}{2}$.

Proof: For a given n -input formula F and its corresponding directed tree $G_g = (V_g, \mathcal{E}_g)$, it follows from (6) that

$$\begin{aligned} \epsilon & \leq \min_i \frac{1}{4|\mathcal{P}_i|} \ln \frac{1}{1 - h(\delta)} \\ & = \frac{1}{4 \max_i |\mathcal{P}_i|} \ln \frac{1}{1 - h(\delta)}. \end{aligned}$$

Now as $\epsilon = \chi(E/|V_g|)$, and χ^{-1} is strictly decreasing, $\epsilon \leq \frac{1}{4 \max_i |\mathcal{P}_i|} \ln \frac{1}{1 - h(\delta)}$ implies that for a given formula and G_g ,

$$E \geq |V_g| \chi^{-1} \left(\frac{1}{4 \max_i |\mathcal{P}_i|} \ln \frac{1}{1 - h(\delta)} \right).$$

We also state some combinatorial properties of trees with a fixed number of leaves.

Lemma 4: Among all directed rooted trees with L leaves and number of children bounded by k , a k -ary balanced tree has the minimum number of non-leaf nodes.

Lemma 5: Among all directed rooted trees with L leaves and number of children bounded by k , a k -ary balanced tree has the minimum depth for the subtree made of non-leaf nodes.

Lemma 6: Among the class of directed rooted trees with bounded children, the minimum depth and minimum size of the subtree consisting of non-leaf nodes are monotone in number of leaves.

Proofs of these lemmas are presented in the Appendix. With these lemmas in hand, we can give the main theorem on minimum energy per input bit.

Theorem 1: For a physical energy-failure function, the minimum energy required to realize any n -input boolean function using a δ -reliable ($\delta < \frac{1}{2}$) formula of gates with degree no more than k (with $k < n$), and each with energy-failure function χ is

$$\frac{n}{k} \chi^{-1} \left(\frac{\ln k}{4 \ln n} \ln \frac{1}{1 - h(\delta)} \right).$$

Proof: A lower bound on energy consumption over all realization circuits (graphs) and all n -input boolean functions can be obtained by minimizing the above realization-specific bound over all realizations and n -input functions:

$$\begin{aligned} E &\geq \min_{F_n, G_g} |V_g| \chi^{-1} \left(\frac{1}{4 \max_i |\mathcal{P}_i|} \ln \frac{1}{1 - h(\delta)} \right) \\ &\geq \left(\min_{F_n, G_g} |V_g| \right) \min_{F_n, G_g} \chi^{-1} \left(\frac{1}{4 \max_i |\mathcal{P}_i|} \ln \frac{1}{1 - h(\delta)} \right) \\ &= \left(\min_{G_g: n \text{ inputs}} |V_g| \right) \min_{G_g: n \text{ inputs}} \chi^{-1} \left(\frac{1}{4 \max_i |\mathcal{P}_i|} \ln \frac{1}{1 - h(\delta)} \right), \end{aligned}$$

where the last equality follows because for each formula there is a gate tree and vice versa.

For a rooted tree $G = (V, \mathcal{E})$, let $\ell(V)$ and $\bar{\ell}(V)$ denote the leaf and non-leaf nodes of a graph G , respectively. Then, it is clear from the relationship between bit graphs and gate graphs that $\bar{\ell}(V_b) = V_g$ and $\mathcal{E}_g = \mathcal{E}_b \cap (V_g \times V_g)$.

As G_g has n inputs, the corresponding G_b has at least n leaves. Thus, one can write

$$\min_{G_g: n \text{ inputs}} |V_g| = \min_{G_b: \geq n \text{ leaves}} \bar{\ell}(V_b).$$

By Lemma 6 and the fact that adding more constraints only increases the minimum we have

$$\min_{G_b: \geq n \text{ leaves}} \bar{\ell}(V_b) = \min_{G_b: n \text{ leaves}} \bar{\ell}(V_b).$$

By Lemma 4, a k -ary G_b achieves the minimum. Now as there are n leaves, in a k -ary tree there are at most $\lceil \frac{1}{k} n \rceil$ nodes in the level above. In turn, there are at most $\lceil \frac{1}{k} \lceil \frac{1}{k} n \rceil \rceil$ in the level above that and so on. This continues until we have only one node at the top level. Thus the total number of non-leaf nodes are lower bounded by

$$\lceil \frac{1}{k} n \rceil + \lceil \frac{1}{k} \lceil \frac{1}{k} n \rceil \rceil + \dots + 1 \geq \frac{n}{k}.$$

This implies that $\min_{F, G_g: n \text{ inputs}} |V_g| \geq \frac{n}{k}$.

To bound the other term note that χ^{-1} is strictly decreasing, so $\chi^{-1} \left(\frac{1}{4 \max_i |\mathcal{P}_i|} \ln \frac{1}{1 - h(\delta)} \right)$ is minimized when $\frac{1}{4 \max_i |\mathcal{P}_i|} \ln \frac{1}{1 - h(\delta)}$ is maximized. This is because $\ln \frac{1}{1 - h(\delta)} \geq 0$, for $\delta < \frac{1}{2}$. Thus when $\max_i |\mathcal{P}_i|$ is minimized the other term is also minimized.

As $\max_i |\mathcal{P}_i|$ is the depth of G_g , by Lemma 5, this minimum is achieved by a k -ary tree. Now, by Lemma 6 and the relation between G_b and G_g , the depth of G_g is minimized when the number of leaves in G_b is minimized. The number of leaves in G_b is no less than n , as there are n inputs. For a k -ary tree with n leaves, the depth is at least $\lceil \frac{\ln n}{\ln k} \rceil \geq \frac{\ln n}{\ln k}$.

Hence,

$$E \geq \frac{n}{k} \chi^{-1} \left(\ln \frac{1}{1 - h(\delta)} \frac{\ln k}{4 \ln n} \right).$$

To understand the implications of Theorem 1, let us consider the simple case where we fix $\delta \in (0, \frac{1}{2})$ and $k = O(1)$. Then, the theorem implies that to realize δ -reliability using gates of at most k inputs, the minimum energy requirement scales with number of inputs n as

$$\Omega \left(n \chi^{-1} \left(\frac{c(\delta, k)}{\ln n} \right) \right),$$

for some constant $c(\delta, k)$.

Typical nanoscale circuits compute functions of large numbers of inputs. As n is large in these circuits, the above order behavior is of fundamental interest. In most practical scenarios (as also under the condition in Theorem 1), χ^{-1} is strictly decreasing and $\lim_{\epsilon \rightarrow 0} \chi^{-1} = \infty$. Thus, as $n \rightarrow \infty$, the term

$$\chi^{-1} \left(\frac{c(\delta, k)}{\ln n} \right) \rightarrow \infty.$$

This implies that the minimum energy requirement per input bit over all boolean functions increases with number of input bits for any $\delta \in (0, \frac{1}{2})$ and $k = O(1)$.

This is in sharp contrast with traditional circuits with noiseless gates. In that case there are various n -input functions that can be realized using $O(n)$ gates. As each gate requires only a constant amount of energy for its perfect operation, the total energy consumption is $O(n)$ for these circuits. Hence, as devices and gates become unreliable there is a price to be paid in terms of the energy per input bit.

Next, we build a more quantitative understanding of the scaling of energy per input bit by considering a few relevant classes of energy-failure dependence functions χ .

B. Energy Bounds for Device Technologies

As discussed before, the energy-failure functions for most device technologies are either polynomial or stretched exponential. The following lower bounds for polynomial and stretched exponential energy-failure dependence follow from Theorem 1.

Corollary 1: The minimum energy required to realize any n -input boolean function using gates with maximum k inputs, $k < n$, and each with $\epsilon = \chi(e)$ is

$$\frac{n}{k c^{\frac{1}{\beta}}} \left(\ln \frac{4\epsilon_0 \ln n}{\ln k} - \ln \ln \frac{1}{1 - h(\delta)} \right)^{\frac{1}{\beta}}$$

when $\chi(e) = \epsilon_0 \exp(-ce^\beta)$, and

$$\frac{n}{k} \left(\frac{4\epsilon_0 \ln n}{\ln k \ln \frac{1}{1 - h(\delta)}} \right)^{\frac{1}{\beta}}$$

when $\chi(e) = \frac{\epsilon_0}{(e+1)^\beta}$.

Proof: Note that both of the energy-failure functions are physical, and so the result follows by substituting the appropriate χ^{-1} in Theorem 1. ■

When we have a lower bound on χ rather than an exact functional form, we can still obtain a lower bound on energy consumption.

Lemma 7: Let energy-failure functions χ_1 and χ_2 be physical and $\chi_1(e) \leq \chi_2(e)$ for all e . For gates with χ_1 if there exists no δ -reliable circuit G_g for a formula F with total energy consumption no more than E , then the same is true for χ_2 gates.

Proof: The result follows by noting that if a per-gate energy e_2 in case of χ_2 achieves δ -reliability, then by the monotonicity of χ_1 and χ_2 , the dominance between them, and condition (6), e_2 energy per gate achieves δ -reliability in case of χ_1 gates. ■

Thus, if we have a lower bound on χ , we can find the fundamental lower bound on energy consumption. This is useful in scenarios where the device physics are not tractable and an exact functional form is hard to derive. Here we use this property to make an interesting generic observation about a broad class of energy-failure functions.

Note that the exponential function $\epsilon = \epsilon_0 \exp(-ce)$ lower bounds polynomial and stretched exponential functions. Thus, by Lemma 7, the exponential function can be used to obtain a lower bound on energy consumption for all

sub-exponential energy-failure functions. Since energy-failure functions for many devices fall in the sub-exponential class and the exponential energy-failure function is also a fundamental thermodynamic limit for CMOS technologies, we can obtain a generic bound using exponential functions.

From Corollary 1 it follows that for $\epsilon = \epsilon_0 \exp(-ce)$, the energy consumption for computing n -input functions is lower bounded by

$$\frac{n}{ck} \left(\ln \ln n - \ln \ln k + \ln(4\epsilon_0) - \ln \ln \frac{1}{1 - h(\delta)} \right). \quad (7)$$

As $k = O(1)$ and so is δ , for large n the leading term is $\frac{n \ln \ln n}{ck}$. So, in the large n regime, as long as $\delta < \frac{1}{2}$, irrespective of δ the minimum energy requirement scales at least as $\frac{n \ln \ln n}{ck}$. This has interesting implications.

First, if gates are error-prone and have sub-exponential energy-failure functions, then to achieve any non-trivial reliability ($\delta < \frac{1}{2}$), the energy requirement per bit of computation scales at least as $c' \ln \ln n$, and this lower bound on scaling is independent of the reliability requirement (as long as it is non-trivial). This means that the reliability requirement is not the bottleneck in obtaining linear scaling of energy with number of inputs. Rather, the bottleneck is the sub-exponential unreliability of the gates.

Second, even if we allow a decreasing reliability requirement with increasing input size, it does not help in obtaining a constant energy consumption per input bit. As long as $\delta_n \uparrow \frac{1}{2}$ such that $h(\delta_n) = 1 - \omega(\frac{1}{n})$, the minimum energy requirement per input bit scales at least as $\ln \ln n$, irrespective of the scaling of δ_n . This can be seen by substituting $h(\delta_n)$ for $h(\delta)$ in (7). This further implies that the fundamental bottleneck is the sub-exponential unreliability of the gates, not the reliability requirement.

V. NON-UNIFORM GATE OPERATING POINTS

Some emerging technologies like spin electronics promise to allow circuits consisting of gates with different operating points, and hence, with different energy consumption levels. In this section, we determine the minimum energy required to compute a given n -input boolean function using a given gate graph if we are allowed to tune the energy of each gate separately.

Let F be an n -input boolean function with a gate (realization) graph G_g , a directed rooted tree. We allocate energy to each gate to ensure that the circuit is δ -reliable and is also energy efficient. Our goal is twofold: to characterize the minimum energy required by a circuit realization while having δ -reliability and to understand the best reliability that can be achieved for a given energy budget.

Using Pippenger's method of information propagation in a circuit [11], [20], [21], one can show that to achieve δ -reliability, for each input bit i , the following must be satisfied.

$$1 - h(\delta) \leq I(F_i(X); X) \leq \prod_{g \in \mathcal{P}_i} (1 - 2\epsilon_g)^2,$$

where $\mathcal{P}_i$ is the path in G_g to the output gate from the gate to which x_i is input. As in the case of uniform gates, this follows by inductively using (3) and (4) along the depth of G_g from root to the terminal gate into which x_i is an input. After some algebra the condition becomes

$$\frac{1}{4} \ln \frac{1}{1 - h(\delta)} \geq \sum_{g \in \mathcal{P}_i} \epsilon_g,$$

where $\epsilon_g = \chi(e_g)$ for each $g \in \mathcal{V}_g$. We introduce the notation $\gamma(\delta) = \frac{1}{4} \ln \frac{1}{1 - h(\delta)}$. Note that as $\epsilon_g \geq 0$, to satisfy the necessary condition for δ -reliability, we only need to consider the *maximal paths* $\{\mathcal{P}_i\}$, where a path $\mathcal{P}_i$ for an input bit i is maximal if there exists no bit $j \neq i$ such that $\mathcal{P}_i \subset \mathcal{P}_j$. Hence, the necessary condition for δ -reliability is

$$\gamma(\delta) \geq \sum_{g \in \mathcal{P}} \epsilon_g, \text{ for all maximal } \mathcal{P}. \quad (8)$$

In a tree G_g , the only maximal paths are the unique *root-to-leaf* paths for each leaf node in G_g .

A. Minimum Energy Requirement

Based on the necessary condition (8), we first determine the minimum energy requirement for δ -reliable realization of F using G_g . Consider the following problem,

$$\begin{aligned} & \min \sum_{g \in V_g} e_g \\ & \text{s.t. } \sum_{g \in \mathcal{P}} \epsilon_g \leq \gamma(\delta) \text{ for all maximal } \mathcal{P}, \\ & \epsilon_g = \chi(e_g) \text{ and } e_g \geq 0 \quad \forall g \in V_g. \end{aligned} \quad (9)$$

Constraints of this problem are the δ -reliability constraints derived above, and the objective is the total energy consumption across the gates. So, the optimal solution of this problem satisfies the necessary conditions for δ -reliability. Hence, the optimum of this problem is a lower bound on the total energy required to realize F using G_g .

For physical energy-failure functions, χ has an inverse, $0 \leq \epsilon_g = \chi(e_g) \leq a$, for $0 \leq e_g \leq \infty$. Hence, the problem can be further simplified by eliminating the energy variable e_g ,

$$\begin{aligned} & \min \sum_{g \in V_g} \psi(\epsilon_g) \\ & \text{s.t. } \sum_{g \in \mathcal{P}} \epsilon_g \leq \gamma(\delta) \text{ for all maximal } \mathcal{P}, \\ & 0 \leq \epsilon_g \leq a \end{aligned} \quad (10)$$

where $\psi = \chi^{-1}$. Note that by Lemma 1, ψ is strictly decreasing, convex, and differentiable. Thus, it turns out that (10) is a convex optimization problem [25]. To obtain a lower bound on energy consumption, one can solve (10) using a general approach for solving convex programs. For a large circuit, however, this can be computationally intensive. Here we derive a simple procedure for obtaining a lower bound which can be used for almost all reasonable requirements on δ . This procedure gives simple closed-form expressions for certain structured circuits and also gives rules of thumb for obtaining lower bounds for general circuits. Towards that we make certain observations about problem (10).

First, note that for any δ , there is a finite $\{e_g\}$ that satisfy the constraints. Hence, the value of the objective is finite for this $\{e_g\}$. On the other hand, suppose at the optimum, for some g , $\epsilon_g = 0$. Then by the definition of physical energy-failure functions we have that $\psi(e_g) = \infty$. This implies an infinite value of the objective. Hence, at the optimum value, $\epsilon_g > 0$ for all $g \in V_g$. Hence, problem (10) remains the same if we remove the condition $\epsilon_g \geq 0$ for all g .

Second, we claim that if the reliability requirement δ is such that

$$h(\delta) \leq 1 - \exp(-4a),$$

then at the optimum of (10), $\epsilon_g < a$ for all $g \in V_g$. This follows by noting that at the optimum, the condition:

$$\sum_{g \in \mathcal{P}} \epsilon_g \leq \gamma(\delta)$$

must be satisfied for all maximal paths $\mathcal{P}$, and by noting that $\gamma(\delta) = \frac{1}{4} \ln \frac{1}{1-h(\delta)}$.

Hence, for reliability requirement δ satisfying $h(\delta) \leq 1 - \exp(-4a)$, the bound on energy consumption can be obtained by solving:

$$\begin{aligned} & \min \sum_{g \in V_g} \psi(\epsilon_g) \\ & \text{s.t. } \sum_{g \in \mathcal{P}} \epsilon_g \leq \gamma(\delta) \text{ for all maximal } \mathcal{P}. \end{aligned} \quad (11)$$

This problem is also a convex problem satisfying Slater's conditions. So, strong duality holds and the KKT conditions are necessary and sufficient conditions for optimality.

In practice, a is at least 0.5, as without any energy the gate outputs a floating binary value at random, which is correct with a probability at least 0.5. Thus, the condition is equivalent to $h(\delta) \leq 0.865$, which is a reasonable reliability requirement in most practical scenarios.

The Lagrangian for problem (11) is

$$\sum_{g \in V_g} \psi(\epsilon_g) + \sum_{\mathcal{P}} \nu_{\mathcal{P}} \left(\sum_{g \in \mathcal{P}_i} \epsilon_g - \gamma(\delta) \right),$$

where $\nu_{\mathcal{P}} \geq 0$, for all $\mathcal{P}$. The KKT conditions are

$$\begin{aligned} \nu_{\mathcal{P}} \left(\sum_{g \in \mathcal{P}} \epsilon_g - \gamma(\delta) \right) &= 0 \quad \forall \mathcal{P}, \\ \sum_{g \in \mathcal{P}} \epsilon_g &\leq \gamma(\delta) \quad \forall \mathcal{P}, \\ \psi'(\epsilon_g) + \sum_{\mathcal{P}: g \in \mathcal{P}} \nu_{\mathcal{P}} &= 0 \quad \forall g. \end{aligned} \tag{12}$$

Now, we use structural properties of the gate graph and the optimization problem to obtain relations between ϵ_g values at the optimum. Consider any node g in the gate graph and its children $g_1, g_2, \dots, g_k$. As the gate graph is a tree, any path $\mathcal{P}_i$ that passes through a g_l , $1 \leq l \leq k$, also passes through g and a path that passes through g_l does not pass through $g_{l'}$, $1 \leq l' \leq k$. So,

$$\sum_{\mathcal{P}: g \in \mathcal{P}} \nu_{\mathcal{P}} = \sum_{l=1}^k \sum_{\mathcal{P}: g_l \in \mathcal{P}} \nu_{\mathcal{P}}.$$

This, together with the KKT conditions (12) imply that for any node g in G_g and its children $g_1, g_2, \dots, g_k$,

$$\psi'(\epsilon_g) = \sum_{l=1}^k \psi'(\epsilon_{g_l}). \tag{13}$$

We make another observation that will be useful later. We claim that at the optimum of (11),

$$\sum_{g \in \mathcal{P}} \epsilon_g = \gamma(\delta), \tag{14}$$

for any maximal path $\mathcal{P}$.

To see this, let us assume the contrary so there is a path $\mathcal{P}'$ such that $\sum_{g \in \mathcal{P}'} \epsilon_g < \gamma(\delta)$. As G_g is a tree, there is a leaf node on $\mathcal{P}'$ through which no other path passes. We can increase ϵ_g for that node until the inequality is matched with equality. This would result in a decrease in total energy, which contradicts the optimality of the present energy allocation. So, condition (14) holds.

The following lemma is useful in deriving the bound on energy consumption.

Lemma 8: Conditions (13) and (14) are necessary and sufficient for $\{\epsilon_g\}$ to be an optimum of problem (11).

Proof: As (11) satisfies Slater's conditions, KKT conditions are necessary and sufficient for optimality. So, (13) derived from KKT conditions is necessary. Necessity of (14) at the optimum has already been argued before.

For proving sufficiency, note that the KKT conditions are sufficient. For each $\mathcal{P}$, $\nu_{\mathcal{P}} = -\psi'(\epsilon_{g_{\mathcal{P}}})$ where $g_{\mathcal{P}}$ is the leaf gate of the path $\mathcal{P}$. It is easy to check that for these choices of $\nu_{\mathcal{P}}$, the KKT conditions are satisfied, given (13) and (14) are satisfied. ■

B. Minimum Energy for Device Technologies

Next, we consider the widely occurring polynomial and exponential energy-failure functions, and discuss how the optimality conditions derived above can be used to obtain minimum energy requirements for symmetric gate graphs. Later, we also present a generic procedure to determine the minimum energy requirement for any tree gate graph and any physical energy-failure function. These procedures also lead to heuristic energy allocation schemes.

1) *Polynomial energy-failure function*: Consider a polynomial energy-failure function $\epsilon_g = \chi(e_g) = \frac{a}{(1+e_g)^\beta}$, as discussed in Sec. III. Note that this function has an inverse $e_g = \psi(\epsilon_g) = \left(\frac{a}{\epsilon_g}\right)^\frac{1}{\beta} - 1$. Note that this inverse function is convex, strictly decreasing and differentiable, $\psi'(\epsilon_g) = -\frac{1}{\beta} a^\frac{1}{\beta} \epsilon_g^\frac{1}{\beta}-1$. Hence, condition (13) becomes

$$\epsilon_g^\frac{1}{\beta}-1 = \sum_{l=1}^k \epsilon_{g_l}^\frac{1}{\beta}-1. \quad (15)$$

Consider a symmetric k -ary tree of depth d as the gate graph, i.e., each gate has k inputs. Now, by symmetry and by condition (14), each gate at depth d must have the same energy and hence, the same failure probability, say ϵ at the optimum of (11). Now, again by symmetry and condition (14), each gate at depth $d-1$ must have the same failure probability, say ϵ' . By condition (15), we have that

$$\epsilon'^\frac{1}{\beta}-1 = k\epsilon^\frac{1}{\beta}-1,$$

which implies that

$$\epsilon' = k^\frac{\beta}{1-\beta} \epsilon.$$

By following this procedure one can argue that at depth i all the gates have the same failure probability $\epsilon(i)$ given by

$$\epsilon(i) = k^\frac{(d-i)\beta}{1-\beta} \epsilon.$$

Now, by condition (14) it follows that

$$\sum_{i=0}^d \epsilon(i) = \gamma(\delta),$$

so we have

$$\epsilon \frac{1 - \tilde{k}^{d+1}}{1 - \tilde{k}} = \gamma(\delta),$$

where $\tilde{k} = k^\frac{\beta}{1-\beta} < 1$. This gives the optimum ϵ to be

$$\epsilon^* = \frac{\gamma(\delta)(1 - \tilde{k})}{1 - \tilde{k}^{d+1}}.$$

So, the minimum energy requirement is given by the total energy consumed at this optimum allocation:

$$\begin{aligned} \sum_{i=0}^d \psi(\epsilon(i)) k^i &= \sum_{i=0}^d k^i \left(\left(\frac{a}{\epsilon^* \tilde{k}^{d-i}} \right)^\frac{1}{\beta} - 1 \right) \\ &= \sum_{i=0}^d (k \tilde{k}^\frac{1}{\beta})^i \tilde{k}^\frac{-d}{\beta} \left(\frac{a}{\epsilon^*} \right)^\frac{1}{\beta} - \sum_{i=0}^d k^i \\ &= \Omega(n), \end{aligned}$$

where the last line follows by noting that $k^{d+1} = \Theta(n)$.

Observe that in this example of a symmetric circuit with non-uniform energy allocation, a linear scaling of energy with the number of inputs is possible. This is in contrast to the circuits with uniform operating points, where linear scaling is not possible.

Note that as in Sec. IV, for any circuit (including one with reliable components) with n inputs, energy scaling is at least $\Omega(n)$. This is because for n inputs we need at least $\frac{n}{k}$ gates, and each gate must consume $\Omega(1)$ energy. For reliable components this is obvious, as the energy consumption per gate is constant and does not need to be tuned. For circuits with unreliable components, if there is a gate that consumes $o(1)$ energy, then $\epsilon = \chi(o(1))$ for that gate is $\omega(1)$. Then, the necessary condition $\sum_{g \in \mathcal{P}} \epsilon_g \leq \gamma(\delta)$ cannot be satisfied for any finite δ for the maximal path through that gate, when n scales.

Remark 1: For symmetric gate graphs with polynomial energy-failure functions, we obtain the following rule of thumb for failure allocation: ϵ should be geometric along the depth with a factor $k^\frac{\beta}{1-\beta}$ from a layer to the one above. This in turn gives a rule of thumb for energy allocation: a ratio of $k^\frac{1}{\beta-1}$ is maintained from a layer to the one above for $1 + e_g$.

2) *Exponential energy-failure function*: Now, we consider the exponential energy-failure function, $\epsilon_g = a \exp(-c e_g)$ with inverse $\psi(\epsilon_g) = -\frac{1}{c} \ln \frac{\epsilon_g}{a}$. Clearly, this function is convex, strictly decreasing, and differentiable, $\psi'(\epsilon_g) = -\frac{a}{c \epsilon_g}$. Thus, condition (13) becomes

$$\frac{1}{\epsilon_g} = \sum_{l=1}^k \frac{1}{\epsilon_{g_l}}. \quad (16)$$

If we consider the same symmetrical k -ary tree as the gate graph, following the same approach as for polynomial energy-failure functions, for gates at depth i and $i+1$ we have

$$\epsilon(i) = \frac{1}{k} \epsilon(i+1).$$

So, following the same steps as for polynomial energy-failure functions we obtain

$$\epsilon^* = \frac{\gamma(\delta)(1 - \frac{1}{k})}{1 - \frac{1}{k^{d+1}}}. \quad (17)$$

Thus, the rest of the derivation of the lower bound follows by replacing $\tilde{k}$ in Sec. V-B1 by $\frac{1}{k}$ and $\psi(\epsilon_g) = -\frac{1}{c} \ln \frac{\epsilon_g}{a}$. Minimum energy consumption is given by

$$\begin{aligned} \frac{1}{c} \sum_i k^i \ln \frac{a k^{d-i}}{\epsilon^*} &= \frac{1}{c} \sum_i \left((d-i) k^i \ln k + k^i \ln \frac{a(1 - \frac{1}{k^{d+1}})}{\gamma(\delta)(1 - \frac{1}{k})} \right) \\ &= \Omega(n). \end{aligned}$$

Notice that the energy allocations for gates at depth i and $i+1$ follow

$$\exp(-c(e(i) - e(i+1))) = \frac{1}{k},$$

implying $e(i) = e(i+1) + \frac{1}{c} \ln k$.

Remark 2: For exponential energy-failure function and symmetric gate graph, though the rule of thumb of ϵ allocation is geometric upwards in the tree (with a factor k), the energy allocation is additive with a factor proportional to $\ln k$.

3) *Generic Procedure*: In general, a numerical value for the minimum energy requirement can be obtained by solving the convex optimization problem (11) directly for a given δ . This would also give an allocation $\{\epsilon_g\}$ and an energy allocation $\{e_g\}$. This solution can be used as a procedure for energy allocation in circuits. Note that this would only be a heuristic energy allocation procedure and not a provably optimum one for achieving δ -reliability, as (11) only gives necessary conditions. Though, note no energy allocation scheme can have δ -reliability with a total energy less than the optimum objective of (11).

In Alg. 1, we give a procedure which is computationally simpler than solving the convex optimization problem (11) using a generic convex optimization algorithm. This procedure builds on the optimality conditions (13) and (14).

Let us define $\mathfrak{P}(\text{Subtree}, g)$ as the sum of ϵ_g along any path from root of the subtree to a leaf through g . Let $\mathcal{S}(g)$ be the sibling nodes of g in the gate graph and $\text{subtree}(g)$ be the subtree rooted at g .

Algorithm 1 Minimum Energy Allocation

Input: $\gamma(\delta)$

Initialize: $\forall g, \epsilon_g = 0, \bar{\epsilon}_g = 1, \gamma = \gamma(\delta)$

Parameters: $0 < \eta \ll 1$

1: Call $\text{SUBTREEALLOC}(\gamma(\delta), G_g)$.

2: Allocate $\psi(\epsilon_g)$ energy to gate g

This algorithm starts by allocating some ϵ to the nodes at lowest depth that are siblings and tunes ϵ according to a binary search while adjusting ϵ values of other nodes according to conditions (13) and (14). For any allocations of ϵ values to the children of a node, it uses condition (13) to obtain the allocation of their parent. Note that

Algorithm 2 SUBTREEALLOC(γ , Subtree(root))

```

1: Among nodes at maximum depth pick  $g$  with smallest index
2: Assign  $\epsilon_g = \frac{\underline{\epsilon}_g + \bar{\epsilon}_g}{2}$  to  $g$ 
3: while  $|\mathfrak{P}(\text{Subtree}, g) - \gamma| > \eta\gamma$  do
4:   if  $\mathfrak{P}(\text{Subtree}, g) - \gamma > \gamma\eta$  then
5:      $\bar{\epsilon}_g \leftarrow \epsilon$ 
6:   else
7:      $\underline{\epsilon}_g \leftarrow \epsilon$ 
8:   end if
9:   Assign  $\epsilon = \frac{\underline{\epsilon}_g + \bar{\epsilon}_g}{2}$  to  $g$ 
10:  Obtain  $\epsilon_{g'}$  by solving  $\min_{\epsilon} \psi(\epsilon) - \epsilon \sum_{g \in \text{child}(g')} \psi'(\epsilon_g)$ 
11:  for  $v \in \mathcal{S}(g')$  (in numerical order) do
12:    SUBTREEALLOC( $\mathfrak{P}(\text{Subtree}(g), g)$ , Subtree( $v$ ))
13:  end for
14: end while
15: For all  $u \in \mathcal{S}(g)$ , reset  $\underline{\epsilon}_u = 0, \bar{\epsilon}_u = 1$ , but keep  $\epsilon_u$ 

```

solving (13) is the same as solving the one-dimensional unconstrained convex optimization problem in step 10 of SUBTREEALLOC. This is because ψ is convex, and hence, the optimality condition for step 10 is the derivative being 0. This derivative condition is the same as (13). We write the step 10 in this fashion to show that (13) is easily solvable, given the ϵ values of child nodes. When a node has an allocation of ϵ , then using (14) one can enforce conditions on ϵ values of other sibling nodes. The sub-routine SUBTREEALLOC carries out this procedure recursively. It is not hard to show that this algorithm reaches the optimum of (11).

Proposition 1: The generic energy allocation procedure reaches the optimum of (11) in $O(|V_g| Q \log \frac{1}{\eta})$ steps, where Q is the number of steps required to solve the one-dimensional convex optimization problem in Step 10 of SUBTREEALLOC.

Proof: Proof of this result builds on Lemma 8. Note that at the optimum of (11), conditions (13) and (14) are satisfied with path sums being $\gamma(\delta)$. Conditions (13) and (14) constrain failure values of all nodes while leaving only one free parameter.

This implies that if the conditions (13) and (14) are enforced, then for a given choice of ϵ for a leaf node at the maximum depth, failure values of all other nodes become fixed (as a function of ϵ). Thus it is then sufficient to do a binary search over ϵ . The algorithm does exactly that.

Note that at the end of the algorithm, the conditions (13) and (14) are satisfied with path sum being $\gamma(\delta)$ from any leaf node. As this is a necessary and sufficient condition for optimality, the output of the algorithm is the optimum.

The complexity result follows because for a given value of ϵ on a leaf node, one has to iterate through all nodes and enforce conditions (13) and (14), which takes $O(|V_g|)$ time. In addition, in each iteration, solving the optimization problem in Step 10 takes Q queries. As we have to do binary search for ϵ up to an accuracy η , the $\log \frac{1}{\eta}$ factor follows. ■

C. Maximum Reliability

Let us consider the case where there is a given energy budget E for the whole circuit. Then, the necessary condition for δ -reliability is

$$\begin{aligned}
\sum_{g \in \mathcal{P}} \epsilon_g &\leq \gamma(\delta) \text{ for all maximal } \mathcal{P}, \\
\sum_{g \in G_g} \epsilon_g &\leq E, \\
\epsilon_g &= \chi(e_g) \text{ and } e_g \geq 0 \quad \forall g,
\end{aligned} \tag{18}$$

Here we are interested in determining the maximum reliability achievable for a given circuit energy budget. We consider the following optimization problem for determining maximum reliability.

$$\begin{aligned}
& \min y \\
& \text{s.t. } \sum_{g \in \mathcal{P}} \epsilon_g - y \leq 0, \text{ for all maximal } \mathcal{P}, \\
& \sum_g \psi(\epsilon_g) \leq E, \\
& 0 \leq \epsilon_g \leq a \quad \forall g \in V_g.
\end{aligned} \tag{19}$$

Let $y_{\min}(E)$ be the solution of problem (19). Note that $\gamma : [0, \frac{1}{2}] \rightarrow [0, \infty)$ is a strictly increasing function of δ on $[0, \frac{1}{2}]$ and is bijective. Hence, inverse of γ exists and it is strictly increasing as well. This implies $\gamma^{-1}(y_{\min}(E))$ is the minimum δ for which a feasible $\{e_g\}$ exists that satisfies the necessary conditions.

Note that the optimum is strictly decreasing with increasing E . To see this, we consider $E' > E$, then the optimal solution for budget E is a feasible solution for the problem with budget E' . Now use this allocation with additional $\frac{E'-E}{|V_g|}$ energy per gate. This is a feasible solution for the problem with budget E' . This feasible solution gives a y value strictly less than $y_{\min}(E)$, as χ is strictly decreasing. Hence, $y_{\min}(E') < y_{\min}(E)$. Also, as $E \rightarrow \infty$, $y_{\min}(E) \rightarrow 0$. This is easy to see by picking $\epsilon_g = \frac{E}{|V_g|}$ for all g , and noting that $\sum_{g \in \mathcal{P}} \epsilon_g \leq \chi\left(\frac{E}{|V_g|}\right) \max_{\mathcal{P}} |\mathcal{P}| \rightarrow 0$ as $E \rightarrow \infty$. Thus the optimum solution of (19), $y_{\min}(E)$ goes to 0 as $E \rightarrow \infty$.

By the property of physical energy-failure functions, namely $\chi(e_g) \rightarrow 0$ as $e_g \rightarrow \infty$ and χ strictly decreasing, the conditions $0 \leq \epsilon_g$ are redundant for any finite energy budget. Also, as $y_{\min}(E) \rightarrow 0$ when $E \rightarrow \infty$, there exists E_{th} such that for all $E \geq E_{th}$, $y_{\min}(E) < a$. Thus, for $E \geq E_{th}$, $\epsilon_g < a \quad \forall g$ are redundant conditions.

Though we do not have a closed-form expression for E_{th} , it is easy to compute. Note that, if for a given budget E , the optimal solution of (20) is y^* , then E is the optimal solution of (11) for $\gamma(\delta) = y^*$. This can be proved by contradiction. Note that the optimal solution of (20) is a feasible solution of (11). Now, if for a given $\gamma(\delta) = y^*$, the optimal solution of (11) is strictly less than E , then it implies that we can divide the excess (E minus the minimum) energy among all the gates to improve y^* in (20), which is a contradiction. This implies that to compute E_{th} we can run Alg. 1 for $\gamma(\delta) = a$.

Now we focus on maximum reliability for an energy budget $E \geq E_{th}$, as in most cases $a = 0.5$ and $\gamma(\delta) < 0.5$ is a bare-minimum reliability requirement. So, we consider the following problem.

$$\begin{aligned}
& \min y \\
& \text{s.t. } \sum_{g \in \mathcal{P}} \epsilon_g - y \leq 0, \text{ for all maximal } \mathcal{P}, \\
& \sum_g \psi(\epsilon_g) \leq E.
\end{aligned} \tag{20}$$

By convexity of ψ , this is a convex optimization problem. As in the case of minimum-energy allocation, we can find sufficient conditions for optimality from KKT conditions. The conditions are: for $\lambda_{\mathcal{P}} \geq 0$ and $\mu \geq 0$,

$$\begin{aligned}
& \sum_{\mathcal{P}} \lambda_{\mathcal{P}} = 1 \\
& \sum_{\mathcal{P}: g \in \mathcal{P}_i} \lambda_{\mathcal{P}} + \mu \psi'(\epsilon_g) = 0, \\
& \mu \left(\sum_{g \in V_g} \psi(\epsilon_g) - E \right) = 0, \\
& \lambda_{\mathcal{P}} \left(\sum_{g \in \mathcal{P}} \epsilon_g - y \right) = 0.
\end{aligned}$$

The following conditions are more useful as they do not involve dual variables.

$$\psi'(\epsilon_g) = \sum_{l=1}^k \psi'(\epsilon_{g_l}). \tag{21}$$

$$\sum_{g \in \mathcal{P}} \epsilon_g = y_{\min}(E), \quad (22)$$

$$\sum_g \psi(\epsilon_g) = E, \quad (23)$$

for any maximal path $\mathcal{P}$ from a leaf to the root. The following lemma states the above conditions are necessary and sufficient for optimality.

Lemma 9: Conditions (21)–(23) are necessary and sufficient for the optimality of (20).

Proof: Necessity of (21) follows from the necessity of KKT conditions.

Necessity of (22) follows because at the optimum, path-sums of ϵ along all the maximal paths must match. Else, there is a path $\mathcal{P}$ for which an ϵ path-sum is smaller. Then one can take a little energy from the leaf gate in that path and distribute it equally among leaf gates of all other paths. One can choose the amount of to be arbitrarily small such that this reallocation of energy (a) decreases path-sums of all paths other than $\mathcal{P}$, (b) increases the path-sum of $\mathcal{P}$, and (c) keeps the path-sum of $\mathcal{P}$ as the smallest. This strictly decreases y , which contradicts the optimality of the current allocation.

Necessity of (23) follows because if there is a strict inequality, then we can always distribute the remaining energy to the gates and decrease ϵ of each gate, resulting in a decrease in y . This is in contradiction to optimality.

For sufficiency of (21)–(23), take $\lambda_{\mathcal{P}} = \frac{\psi'(\epsilon_{g_{\mathcal{P}}})}{\sum_{\mathcal{P}} \psi'(\epsilon_{g_{\mathcal{P}}})}$, where $g_{\mathcal{P}}$ is the leaf of $\mathcal{P}$ and take $\mu = -\frac{1}{\sum_{\mathcal{P}} \psi'(\epsilon_{g_{\mathcal{P}}})}$. Then, it is easy to check that these $\lambda_{\mathcal{P}}$ and μ satisfy KKT conditions. ■

To derive the best reliability achievable for a given energy budget, we can use the same approach. First, for a given ϵ at the maximum depth, find ϵ for all other nodes using (21) and (22), and then using $\sum_g \chi(\epsilon_g) = E$, obtain ϵ at the maximum depth. This would eventually give the sum of ϵ_g along any path, and hence, $y_{\min}(E)$.

D. Maximum Reliability for Device Technologies

1) *Polynomial energy-failure function:* By the same symmetry arguments as before, gates at the same depth must have same failure probabilities. Also, by the conditions (21)–(22):

$$\epsilon(i) = \tilde{k}\epsilon(i+1).$$

So, if the failure probability at depth i is $\epsilon(i)$ and energy budget is E , then we must have

$$\begin{aligned} E &= \sum_{i=0}^d \psi(\epsilon(i)) k^i \\ &= \sum_{i=0}^d k^i \left(\left(\frac{a}{\epsilon(d) \tilde{k}^{d-i}} \right)^{\frac{1}{\beta}} - 1 \right) \\ &= \sum_{i=0}^d (k \tilde{k}^{\frac{1}{\beta}})^i \tilde{k}^{-\frac{d-i}{\beta}} \left(\frac{a}{\epsilon(d)} \right)^{\frac{1}{\beta}} - \sum_{i=0}^d k^i \\ &= \epsilon(d)^{-\frac{1}{\beta}} \sum_{i=0}^d (k \tilde{k}^{\frac{1}{\beta}})^i \tilde{k}^{-\frac{d-i}{\beta}} a^{\frac{1}{\beta}} - \sum_{i=0}^d k^i, \end{aligned}$$

which gives $\epsilon(d)$ in terms of E .

The best δ that can be achieved is

$$\gamma^{-1} \left(\sum_{i=0}^d \epsilon(i) \right) = \gamma^{-1} \left(\epsilon(d) \frac{1 - \tilde{k}^{d+1}}{1 - \tilde{k}} \right).$$

2) *Exponential energy-failure function*: Following the same steps as in the case of polynomial energy-failure functions we obtain a similar expression for $\epsilon(d)$ in terms of E ,

$$\begin{aligned} E &= \sum_{i=0}^d k^i \frac{1}{c} \ln \frac{a}{\epsilon(i)} \\ &= \frac{1}{c} \sum_{i=0}^d k^i \left(\ln \frac{a}{k^{d-i}} - \ln \epsilon(d) \right), \end{aligned}$$

which implies

$$\epsilon(d) = \exp \left(- \frac{cE - \sum_{i=0}^d k^i \ln \frac{a}{k^{d-i}}}{\sum_{i=0}^d k^i} \right),$$

and

$$\gamma(\delta) = \epsilon(d) \frac{1 - \frac{1}{k^{d+1}}}{1 - \frac{1}{k}}.$$

3) *General procedure*: A general procedure of energy allocation can be obtained by solving the convex optimization problem (20). As in minimum energy allocation, a computationally simpler approach would be to use the necessary and sufficient KKT conditions. Though, we take a different approach here: we design a new procedure using minimum energy allocation as a sub-routine, see Alg. 3. Similar complexity and accuracy guarantees hold with an additional multiplicative factor of $\log \frac{1}{\theta}$ in the computational complexity, where θ is the energy budget accuracy $(1 \pm \theta)E$.

The following lemma is useful in proving the accuracy of Alg. 3.

Lemma 10: For a given energy budget E , y_{min} is the optimum of (20) if and only if for a given reliability requirement $\gamma(\delta) = y_{min}$, E is the optimum of (11).

Proof: As argued before, recall that for a physical energy-failure function, $y_{min}(E)$ is strictly decreasing function of E , $y_{min} : [0, \infty) \mapsto [0, \infty]$, which is one-to-one and onto.

We start with the direct part. As E meets $\gamma(\delta)$ reliability requirement in (11) for an allocation of ϵ_g , in (20) this ϵ_g allocation meets the budget E while achieving a $\gamma(\delta)$ reliability. So, $y_{min}(E) \leq \gamma(\delta)$. Let $y_{min}(E) < \gamma(\delta)$, then we can take away some energy from some gates in the circuit, so that their ϵ_g increases and $\sum_{g \in \mathcal{P}} \epsilon_g = \gamma(\delta)$ for all maximal $\mathcal{P}$. This implies that the total energy used is less than E while achieving $\gamma(\delta)$ reliability, which is a contradiction.

The converse follows similarly by starting with an allocation that achieves maximum reliability $y_{min}(E)$ for a given budget E and showing that E is the minimum energy requirement for a given reliability criteria $\gamma(\delta) = y_{min}(E)$. Proof follows similarly by showing an inequality, and then showing that a strict inequality is a contradiction. ■

Based on the above lemma, in Alg. 3 we do a binary search over δ to find the minimum δ for which minimum energy allocation obtained is E .

Proposition 2: The generic energy allocation procedure reaches the optimum of (20) in $O(|V_g| Q \log \frac{1}{\eta})$ steps for a given θ if $E \geq E_{th}$, where Q is the number of steps required to solve the one-dimensional convex optimization problem in Step 10 of SUBTREEALLOC.

Proof: By Lemma 10 as there is a unique δ for an energy budget, it is sufficient to search over all δ so that we find a δ for which E is the minimum energy requirement. Hence, doing a binary search for δ and running the minimum energy procedure for each δ converges to the correct reliability requirement.

Complexity guarantees follow similarly as in the case of minimum energy procedure. Note that here we have to do an additional binary search for δ . But as it is over $[0, 1]$, this search takes $O(1)$ iterations which is included in the constants in the complexity order result. ■

We would like to stress again that the energy allocation rules in this section are derived from the necessary conditions for δ -reliability. Hence, they are heuristics for the purpose of achieving δ -reliability. But, as they are derived based on the necessary conditions, no energy allocation scheme can achieve a better energy consumption (for a given reliability) or reliability (for a given energy budget) than the bounds obtained by these allocation schemes.

Algorithm 3 Maximum Reliability Allocation

Input: E **Initialize:** $\forall g, \epsilon_g = 0, \bar{\epsilon}_g = 1, \gamma = \gamma(\delta)$ **Parameters:** $0 < \eta \ll 1, 0 < \theta \ll 1$

```

1:  $\underline{\delta} = 0, \bar{\delta} = 1, \delta = \frac{1}{2}$ .
2: while  $|\sum_g \psi(\epsilon_g) - E| > \theta E$  do
3:   if  $\sum_g \psi(\epsilon_g) - E > \theta E$  then
4:      $\underline{\delta} \leftarrow \delta$ 
5:   else
6:      $\bar{\delta} \leftarrow \delta$ 
7:   end if
8:    $\delta = \frac{\underline{\delta} + \bar{\delta}}{2}$ 
9:   Call SUBTREEALLOC( $\gamma(\delta), G_g$ )
10: end while
11: Allocate  $\psi(\epsilon_g)$  energy to gate  $g$ 

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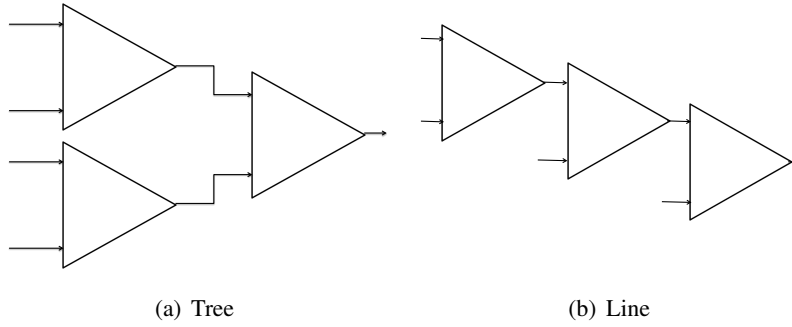


Fig. 1. Tree and line circuit structures.

VI. NUMERICAL EXAMPLES

In previous sections, we obtained a heuristic for energy allocation en route to bounding reliability. In this section we try to understand the performance of the heuristics numerically in simple settings. As this work is primarily concerned with obtaining fundamental energy-reliability bounds, an expansive and detailed study of energy allocation methods is out of scope.

For the purpose of our simple numerical studies, we consider three different boolean functions widely used in information theory and computer science: conjunction, disjunction, and parity. We study circuits constructed with AND gates for conjunction, circuits constructed with OR gates for disjunction, and circuits constructed with XOR gates for parity. In all cases we consider 2-input gates with exponential energy-failure functions, the fundamental thermodynamic bound for CMOS devices [24].

A conjunction circuit is constructed with AND gates in two main ways, line graph and symmetric tree, as in Fig. 1. The same is true for disjunction circuit constructed with OR gates and parity circuits constructed with XOR gates. We study reliability of both configurations for each of these three types of circuits, under the heuristic energy allocation schemes. Though the energy allocation scheme is applicable to any n -input boolean function, in this section we restrict ourselves to 4-input boolean functions. Small circuits are insightful since we can compute and precisely evaluate closed-form expressions for reliability.

For the exponential energy-failure function $\epsilon = \epsilon_0 \exp(-ce_g)$, in most cases $\epsilon_0 = 0.5$, as the output is perfectly random when no energy is allocated to the gate. Here we study the reliability of the circuits for a given energy budget, $E \geq \sum_g e_g$. For convenience we specify the budget in terms of cE such that $cE \geq \sum_g (ce_g) = \sum_g \ln \frac{\epsilon_0}{\epsilon_g}$.

Note that though the heuristic depends on the circuit structure, it is not affected by the types of gates. Hence, the energy allocation under the heuristic would be same for conjunction, disjunction, and parity. For the line circuit, it is not hard to see that the heuristic allocation rule gives uniform energy allocation. On the other hand, for tree

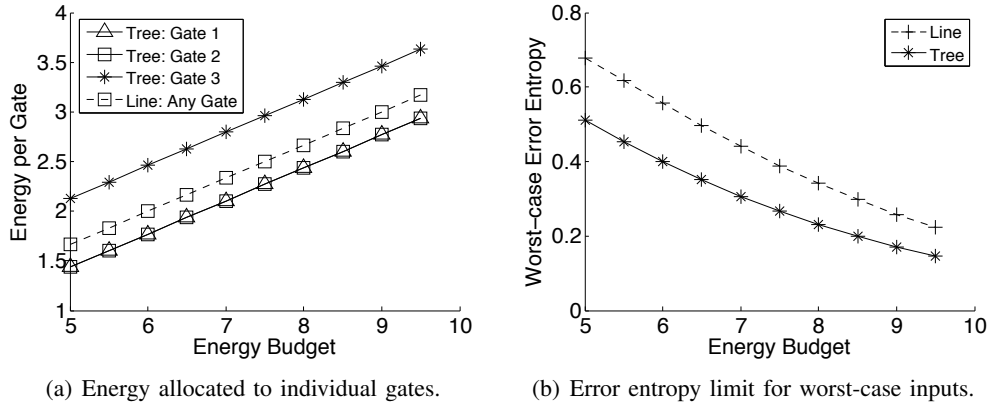


Fig. 2. Energy allocation and worst-case error entropy.

circuits, the heuristic allocation gives different energies to the gates. In Fig. 2(a) we plot the energy allocated to each gate (ce_g) for different energy budgets (cE). Note that under the heuristic scheme, the output gate (gate 3) is allocated more energy to increase its reliability.

As discussed before, δ -reliability is equivalent to worst-case (across all input patterns) error entropy, $h(\delta)$ (for $\delta \leq 0.5$). Fig. 2(b) plots the limit of worst-case error entropy against different energy budgets. We observe that the tree graph has a better worst-case entropy bound than the line graph.

Next, we study the individual boolean functions separately. The measure of performance we choose is conditional error entropy, $H(E|X_1, X_2, \dots, X_n)$, where E is the binary error variable and $\{X_i\}$ are binary input variables, as this also captures the effects of inputs on the error entropy. For each boolean function, we compute closed-form expressions for $H(E|X_1, X_2, \dots, X_n)$ for both tree and line graphs in terms of ϵ_g for each gate. Then, we evaluate these omitted expressions for each energy (and hence ϵ_g) allocation.

For each boolean function, we study conditional error entropy for line graph under the heuristic allocation, conditional error entropy for tree under the heuristic allocation, and conditional error entropy for tree under uniform energy allocation. Note that the heuristic allocation gives uniform allocation for line graph.

Fig. 3(a) plots the conditional error entropy again energy budget for conjunction. We observe that the tree graph with heuristic energy allocation performs better than line graph with heuristic energy allocation (which is also uniform allocation). We also observe that tree graph with uniform energy allocation has a better error performance than line graph. From these one may argue that for conjunction a tree graph is more reliable than a line graph.

But the same argument is not true for disjunction. In Fig. 3(b) we see that tree graph with uniform energy allocation has a worse error performance than line graph. But, tree graph with heuristic energy allocation performs better than line graph with heuristic energy allocation. In both conjunction and disjunction circuits we observe that the heuristic energy allocation for tree graphs perform better (by 15–18%) than uniform energy allocation.

But, this does not mean that the heuristic allocation is uniformly best. One shortcoming of this heuristic energy allocation is that it optimizes a necessary condition for δ -reliability while ignoring the truth table of individual gates. This is reflected in case of parity circuits in Fig. 3(c). Notice that the error probabilities are the same for both tree and line graphs. If we consider each gate to be a gate plus an independent Bernoulli noise, then error happens if an odd number of gates have Bernoulli noise 1. This is true irrespective of what circuit structure is used. Thus it is clear that all gates are equally critical for reliable realization of this boolean function, and hence, uniform energy allocation is optimal. In summary, though the energy allocation heuristic is a by product of a method to energy-reliability trade-offs, it performs well in some scenarios, but has some limitations too.

VII. CONCLUSION AND FUTURE WORK

We obtained a lower bound on the minimum energy needed to compute an n -input boolean function using unreliable gates. We observed that a superlinear scaling of energy with the number of input bits is unavoidable for sub-exponential energy-failure functions, irrespective of the reliability requirement, when gates are constrained to have uniform operating points. Contrarily, when gates are allowed to have different operating points, minimum

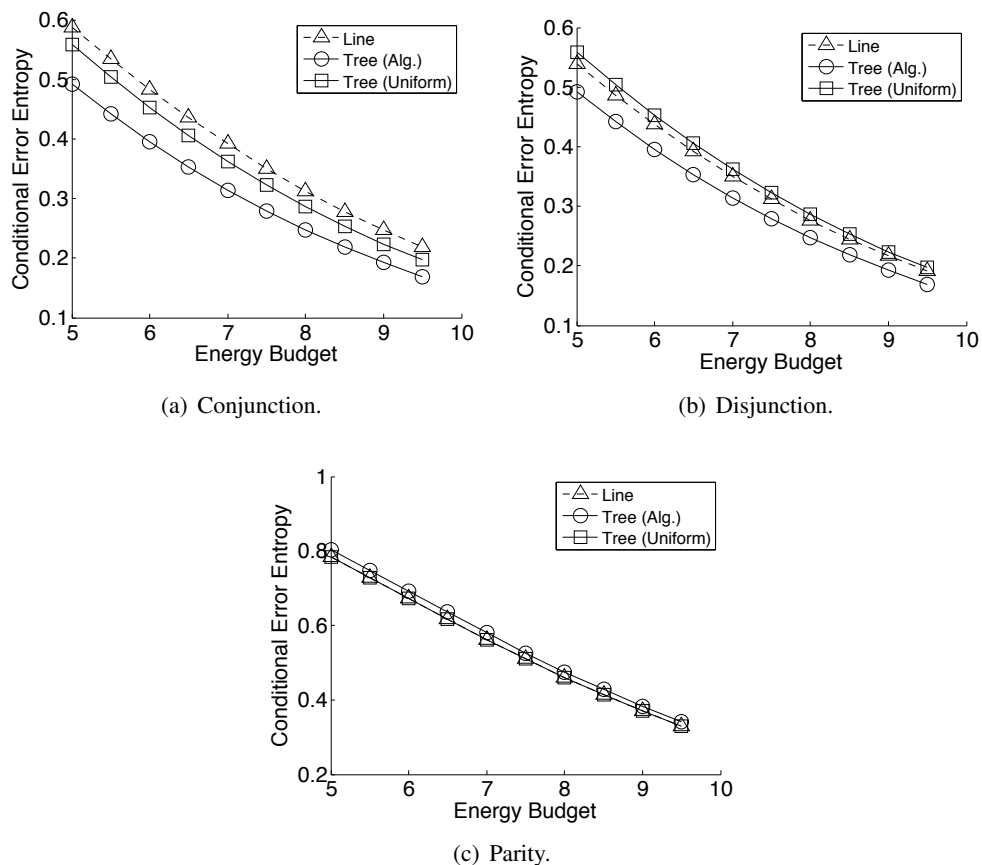


Fig. 3. Conditional error entropy performance under heuristic allocation.

energy requirements for polynomial and exponential energy-failure functions and symmetric circuits demonstrate that the lower bound is linear in the number of inputs. This argues for the value of emerging device technologies that allow variable gate operations. For general circuits and energy-failure functions, we proposed an algorithm that can numerically compute the lower bound in linear time. This procedure also gives a heuristic to allocate energy to different gates. The heuristic energy allocation is generic irrespective of the constituent gate types and optimizes the necessary conditions for δ -reliability. Despite these obvious limitations, this scheme is computationally simple and performs well in many settings. As future work, we aim to develop provably optimal energy allocation schemes with uniform performance guarantees for general circuits.

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APPENDIX

Proof of Lemma 1: First, we establish that χ has an inverse that is one-to-one and strictly decreasing. The proof is standard in real analysis.

Since χ is strictly decreasing, it is one-to-one. Otherwise there would be an $e_1 < e_2$, such that $\chi(e_1) = \chi(e_2)$. From differentiability and therefore continuity of χ , it also follows that χ is onto.

Let $0 < \epsilon < a$ be such that there is no $e_g > 0$ with $\chi(e_g) = \epsilon$ and we show a contradiction. As the function is decreasing, there exists an e such that $\chi(x) < \epsilon$ for all $x > e_g$ and $\chi(x) > \epsilon$ for all $x < e_g$. Consider $\lim_{x \uparrow e_g} \chi(x)$ and $\lim_{x \downarrow e_g} \chi(x)$. For any sequence $\{x_k\} \uparrow e_g$, $\{\chi(x_k)\}$ is monotonic and bounded, so $\lim_k \chi(x_k)$ exists and is finite. Similarly, this is true for $x_k \downarrow e_g$ and $\lim_k \chi(x_k)$. As χ is continuous these two limits match and must equal $\chi(e_g)$. But as $\chi(x) < \epsilon < \chi(x')$ for $x > e_g > x'$, the only possible limit is ϵ . So, $\chi(e_g) = \epsilon$. This implies that $\chi : (0, \infty) \rightarrow (0, a)$ is onto.

So, an inverse exists for one-to-one and onto χ .

To see that χ^{-1} is strictly decreasing, let $0 < \epsilon_1 < \epsilon_2 < a$. Now, there exists e_1 and e_2 such that $e_i = \chi^{-1}(\epsilon_i)$, $i \in \{1, 2\}$. We show that $e_1 \leq e_2$ is not possible. Let $e_1 \leq e_2$, then by the strictly decreasing property of χ , $\chi(e_1) \geq \chi(e_2)$, implying $\epsilon_1 \geq \epsilon_2$, which is contradictory.

Note that the derivative of χ^{-1} at a value ϵ is 1 by the derivative of χ at the value $\chi^{-1}(\epsilon)$, if it is defined. As χ is strictly decreasing, at no point the derivative of χ is 0, and hence, χ^{-1} is differentiable.

Without loss of generality let $e_1 > e_2$, so $\epsilon_1 = \chi(e_1) < \epsilon_2 = \chi(e_2)$, then for $\alpha \in [0, 1]$,

$$\begin{aligned}
 \chi^{-1}(\alpha\epsilon_1 + (1 - \alpha)\epsilon_2) &= \chi^{-1}(\alpha\chi(e_1) + (1 - \alpha)\chi(e_2)) \\
 &\stackrel{(a)}{\leq} \chi^{-1}(\chi(\alpha e_1 + (1 - \alpha)e_2)) \\
 &= \alpha e_1 + (1 - \alpha)e_2 \\
 &= \alpha\chi^{-1}(\epsilon_1) + (1 - \alpha)\chi^{-1}(\epsilon_2),
 \end{aligned} \tag{24}$$

where (a) follows because χ^{-1} is decreasing and χ is convex. This proves convexity of χ^{-1} . ■

Proof of Lemma 4: A directed rooted tree can be seen as a structure where directed lines originate from leaves and are eventually merged at the root node. Each non-leaf node merges lines coming from the level below it. Thus there are L lines to be merged.

As each node can have at most k children, each non-leaf node can merge at most k lines. Each non-leaf node can be thought of as a gadget/entity which can take at most k lines as input and outputs one merged line. Consider any structure of the non-leaves that merges L lines to 1. In any of these structures if there is a non-leaf node with less than k inputs, then replacing that with a non-leaf node with k inputs does not increase the total number of non-leaf nodes. So for any tree there is a k -ary tree with the same number of leaf nodes, and no more non-leaf nodes.

Note that converting a k -ary tree to a balanced k -ary tree with the same number of leaf nodes does not increase the total number of nodes and hence, does not increase the number of non-leaf nodes. ■

Proof of Lemma 5: By similar arguments as in Lemma 4. Note that if there is a tree with certain number of leaves and each node with at most k children, then depth does not increase if we change it to a k -ary tree to same number of leaves. The rest follows by noting that converting a k -ary tree to a balanced k -ary tree with the same number of leaves does not increase the depth. ■

Proof of Lemma 6: Consider two directed trees with L and L' leaves, $L' \geq L$. Then, any graph configuration with L' leaves can be transformed to graph with L leaves without increasing the size (just by dropping $L' - L$ leaves). Hence, the minimum achieving configuration for L' leaves is also a configuration for L leaves. Hence, the minimum in case of L leaves is not larger than the minimum in case of L' leaves. ■